

SCANNING ELECTRON MICROSCOPY/ ENERGY DISPERSIVE X-RAY SPECTROSCOPY (SEM/EDX)

Carl Zeiss AG SUPRATM 25 FE-SEM with Oxford INCA X-Sight

A SEM (Scanning Electron Microscope) can be utilized for high magnification imaging of almost all materials. With SEM in combination with EDX (Energy Dispersive X-Ray spectroscopy) it is also possible to find out which elements are present in the area being viewed. A SEM-EDX is a powerful problem solving instrument to not only identify but also quantify the elemental composition as part of a failure analysis.

KEY FEATURES

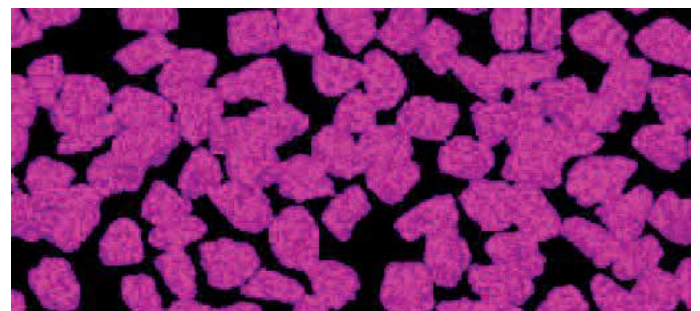
- Ultra high resolution over the full high voltage range
- Minimal adjustment required over the full operating voltage range
- High probe current for fast X-Ray analysis and mapping
- Large 5-axes motorized Cartesian stage for handling a number of smaller specimens simultaneously
- Short analytical working distance of 8.5 mm for simultaneous high resolution imaging and X-Ray analysis

STRENGTHS

- Quick, "first look" compositional analysis
- Versatile
- Quantitation for some samples (flat, polished, homogeneous)

SERVICES

ALS Thailand offers qualitative and semi-quantitative analysis by SEM/ EDX to surfaces of solid samples for the identification of contaminants as well as determination of coating thickness by cross-section (destructive).



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